

| | | | |
|-----------------------------------|---------------------------------------|-------------------------------------------------------------|-------------|
| Notice of References Cited | Application/Control No. 10/702,346 | Applicant(s)/Patent Under Reexamination BRATEK ET AL. | |
| | Examiner Jermie Cozart | Art Unit 3726 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|--------------------|----------------|
| | A | US-6,823,718 B2 | 11-2004 | Sandford et al. | 73/37 |
| | B | US-6,715,360 B1 | 04-2004 | Pepperling et al. | 73/756 |
| | C | US-6,619,129 B2 | 09-2003 | Pitzer, Paul J. | 73/715 |
| | D | US-5,762,439 A | 06-1998 | Siner, Irwin H | 403/359.6 |
| | E | US-5,716,156 | 02-1998 | Bayer et al. | 403/282 |
| | F | US-5,179,861 A | 01-1993 | Asano et al. | 73/726 |
| | G | US-5,158,390 A | 10-1992 | Ito et al. | 403/282 |
| | H | US-4,939,497 | 07-1990 | Nishida et al. | 338/4 |
| | I | US-4,728,216 | 03-1988 | Disborg, Lennart | 403/282 |
| | J | US-4,118,134 | 10-1978 | Mansel, Orin C. | 403/282 |
| | K | US-3,734,697 | 05-1973 | Sieghartner, L. J. | 29/889.23 |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.